APPLICATION NO. CONFIRMATION NO. ATTY. DOCKET NO. FORM PTO-1449 09/728,135 10002360-1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT APPLICANT'S INFORMATION DISCLOSURE Clinton M. Ramsey STATEMENT GROUP FILING DATE (Use several sheets if necessary) Nov. 30, 2000 U.S. PATENT DOCUMENTS REFERENCE DESIGNATION SUB CLASS DOCUMENT NAME EXAMINER CLASS DATE INITIAL NUMBER 183.06 395 Sep. 21, 1999 Ranson et al. 5,956,476 ROF 500.07 Jan. 25, 2000 Chang et al. 395 18 6,018,623 Chon OIP 1C 1D JAN 0 3 2002 1E 1F RADEMARK 1G Technology Contact 2.00 1H 11 **1**J ١K FOREIGN PATENT DOCUMENTS TRANSLATION SUB NAME CLASS DOCUMENT DATE NO YES CLASS NUMBER 1L 1M 1N 10 1P OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.) "Statistical Modeling for Efficient Parametric Yield Estimation of MOS VLSI Circuits" Paul Cox et al., IEEE Trans. Electron. Devices, Vol. ED-32 No. 2, pp. 471-478, 1985 10 Mur 1 R 15 DATE CONSIDERED EXAMINER

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